

# RELIABILITY REPORT





# Reliability Data Report

## Product Family R519

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LTC2704 / LTC2751 / LTC2752 /  
LTC2753 / LTC2754 / LTC2755 /  
LTC2756 / LTC2758

# Reliability Data Report

## Report Number: R519

Report generated on: Wed Oct 03 18:38:52 PDT 2012

OPERATING LIFE TEST					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+125°C) <sup>1</sup>	No. of FAILURES <sub>2,3</sub>
SSOP/TSSOP	154	0630	1109	154	0
QFN/DFN	231	0708	0911	192	0
Totals	385	-	-	346	0

PRESSURE COOKER TEST AT 15 PSIG , +121 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
SSOP/TSSOP	1920	0630	1043	265	0
QFN/DFN	177	0904	1022	15	0
Totals	2,097	-	-	280	0

TEMP CYCLE FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
SSOP/TSSOP	2354	0542	1142	1216	0
QFN/DFN	223	0740	1022	71	0
Totals	2,577	-	-	1,287	0

THERMAL SHOCK FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
SSOP/TSSOP	2294	0542	1142	1230	0
QFN/DFN	201	0740	1022	60	0
Totals	2,495	-	-	1,290	0

HIGH TEMPERATURE BAKE AT 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
SSOP/TSSOP	453	0824	1142	456	0
QFN/DFN	50	0904	0904	25	0
Totals	503	-	-	481	0

(1) Assumes Activation Energy = 0.7 Electron Volts  
(2) Failure Rate Equivalent to +55 °C, 60% Confidence Level =5.3 FITS  
(3) Mean Time Between Failure in Years = 21545.8  
Note: 1 FIT = 1 Failure in One Billion Hours.  
Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 Preconditioning